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ON Semiconductor®

FDMC2D8N025S

N-Channel PowerTrench® SyncFET™

25 V, 124 A, 1.9 mΩ

Features

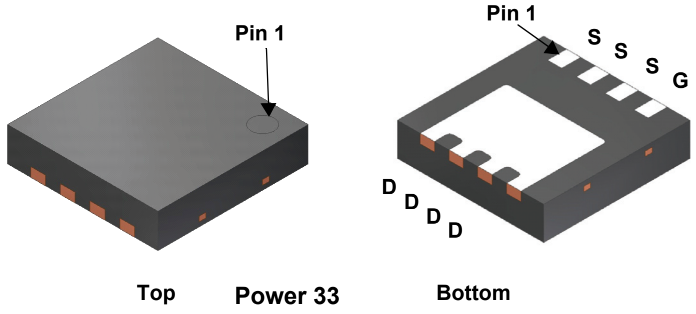
- Max $r_{DS(on)}$ = 1.9 mΩ at V_{GS} = 10 V, I_D = 28 A
- Max $r_{DS(on)}$ = 2.4 mΩ at V_{GS} = 4.5 V, I_D = 25 A
- High Performance Technology for Extremely Low $r_{DS(on)}$
- SyncFET™ Schottky Body Diode
- 100% UIL Tested
- RoHS Compliant

General Description

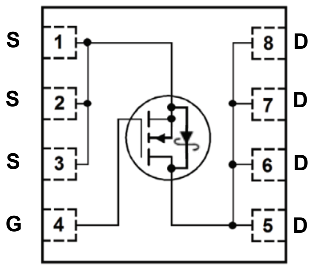
The FDMC2D8N025S has been designed to minimize losses in power conversion application. Advancements in both silicon and package technologies have been combined to offer the lowest $r_{DS(on)}$ while maintaining excellent switching performance. This device has the added benefit of an efficient monolithic schottky body diode.

Applications

- Synchronous Rectifier for DC/DC Converters
- Notebook Vcore/ GPU Low Side Switch
- Networking Point of Load Low Side Switch
- Telecom Secondary Side Rectification



Power 33



MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted.

Symbol	Parameter	Ratings	Units
V_{DS}	Drain to Source Voltage	25	V
V_{GS}	Gate to Source Voltage	±16	V
I_D	Drain Current -Continuous T_C = 25 °C (Note 5)	124	A
	-Continuous T_C = 100 °C (Note 5)	78	
	-Continuous T_A = 25 °C (Note 1a)	28	
	-Pulsed (Note 4)	583	
E_{AS}	Single Pulse Avalanche Energy (Note 3)	96	mJ
P_D	Power Dissipation T_C = 25 °C	47	W
	Power Dissipation T_A = 25 °C (Note 1a)	2.4	
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	2.7	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	53	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMC2D8N025S	FDMC2D8N025S	Power 33	13 ”	12 mm	3000 units

December, 2016, Rev. 1.0

Publication Order Number:
FDMC2D8N025S/D

Electrical Characteristics T_J = 25 °C unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units

Off Characteristics

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain to Source Breakdown Voltage	I_D = 1 mA, V_{GS} = 0 V	25			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 10 mA, referenced to 25 °C		22		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 20 V, V_{GS} = 0 V			500	μA
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±16 V, V_{DS} = 0 V			±100	nA

On Characteristics

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{GS(th)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = 1 mA	1.0	1.6	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 10 mA, referenced to 25 °C		-3		mV/°C
$r_{DS(on)}$	Static Drain to Source On Resistance	V_{GS} = 10 V, I_D = 28 A		1.4	1.9	mΩ
		V_{GS} = 4.5 V, I_D = 25 A		1.8	2.4	
		V_{GS} = 10 V, I_D = 28 A, T_J = 125 °C		2.1	2.9	
g_{FS}	Forward Transconductance	V_{DS} = 5 V, I_D = 28 A		200		S

Dynamic Characteristics

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
C_{iss}	Input Capacitance	V_{DS} = 13 V, V_{GS} = 0 V, f = 1 MHz		3295	4615	pF
C_{oss}	Output Capacitance			833	1170	pF
C_{rss}	Reverse Transfer Capacitance			70	120	pF
R_g	Gate Resistance		0.1	0.8	2.0	Ω

Switching Characteristics

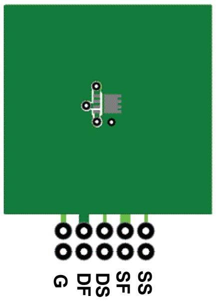
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = 13 V, I_D = 28 A, V_{GS} = 10 V, R_{GEN} = 6 Ω		13	23	ns
t_r	Rise Time			3	10	ns
$t_{d(off)}$	Turn-Off Delay Time			33	52	ns
t_f	Fall Time			3	10	ns
Q_g	Total Gate Charge	V_{GS} = 0 V to 10 V V_{DD} = 13 V, I_D = 28 A		45	63	nC
Q_g	Total Gate Charge	V_{GS} = 0 V to 4.5 V		21	30	nC
Q_{gs}	Gate to Source Charge			7.9		nC
Q_{gd}	Gate to Drain “Miller” Charge			4.1		nC

Drain-Source Diode Characteristics

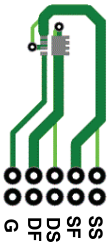
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Source to Drain Diode Forward Voltage	V_{GS} = 0 V, I_S = 2 A (Note 2)		0.7	1.2	V
		V_{GS} = 0 V, I_S = 28 A (Note 2)		0.8	1.3	
t_{rr}	Reverse Recovery Time	I_F = 28 A, di/dt = 236 A/μs		27	43	ns
Q_{rr}	Reverse Recovery Charge			25	40	nC

Notes:

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in^2 pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 53 °C/W when mounted on a 1 in^2 pad of 2 oz copper



b) 125°C/W when mounted on a minimum pad of 2 oz copper

2. Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.
3. E_{AS} of 96 mJ is based on starting T_J = 25 °C, L = 3 mH, I_{AS} = 8 A, V_{DD} = 25 V, V_{GS} = 10 V. 100% tested at L = 0.1 mH, I_{AS} = 27 A.
4. Pulse Id please refer to Fig.11 SOA curve for detail.
5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

Typical Characteristics T_J = 25 °C unless otherwise noted.

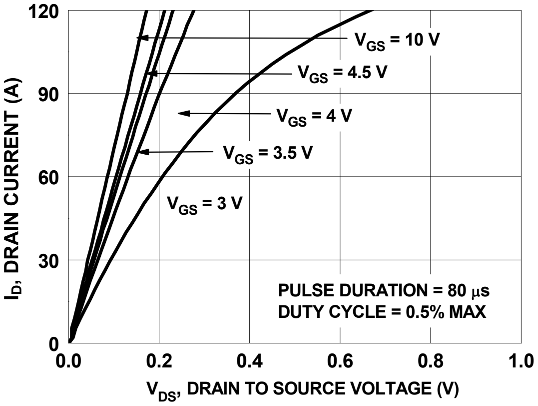


Figure 1. On Region Characteristics

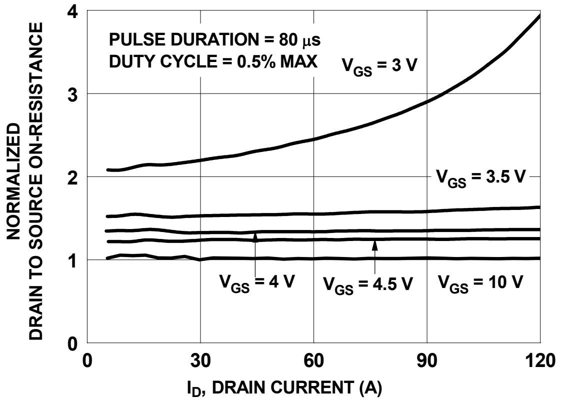


Figure 2. Normalized On-Resistance vs. Drain Current and Gate Voltage

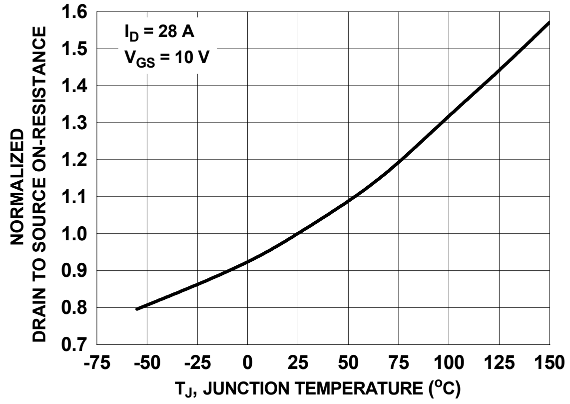


Figure 3. Normalized On Resistance vs. Junction Temperature

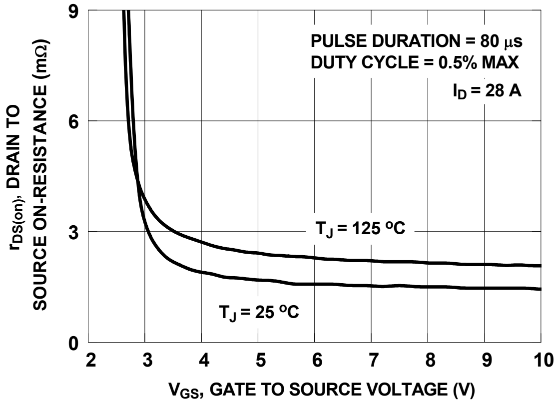


Figure 4. On-Resistance vs. Gate to Source Voltage

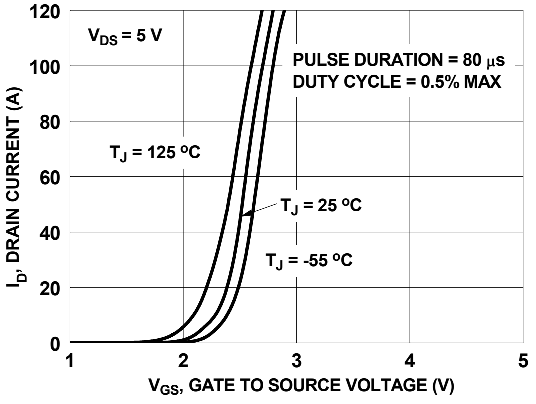


Figure 5. Transfer Characteristics

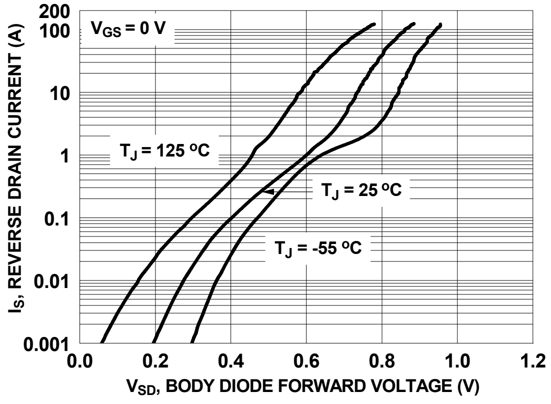


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

Typical Characteristics T_J = 25 °C unless otherwise noted.

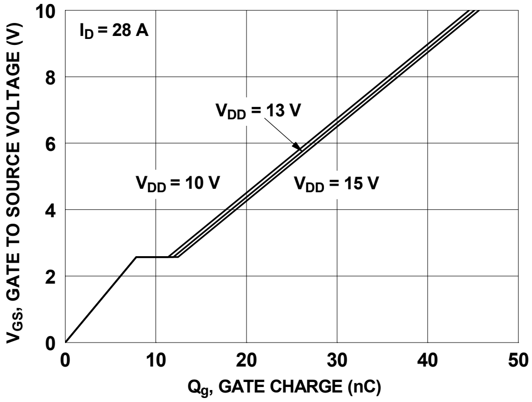


Figure 7. Gate Charge Characteristics

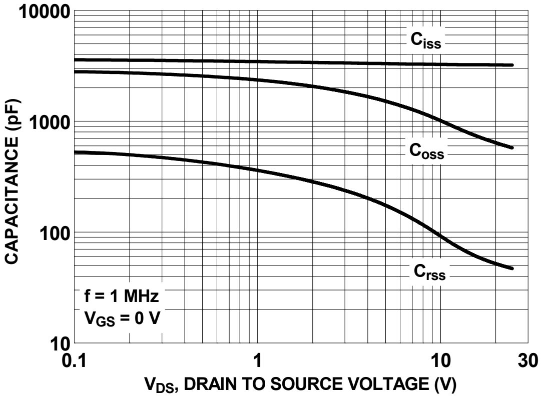


Figure 8. Capacitance vs. Drain to Source Voltage

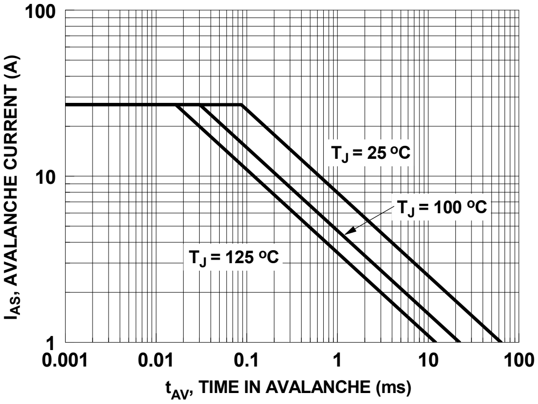


Figure 9. Unclamped Inductive Switching Capability

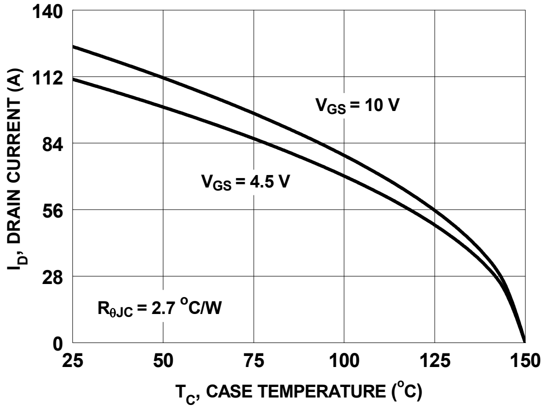


Figure 10. Maximum Continuous Drain Current vs Case Temperature

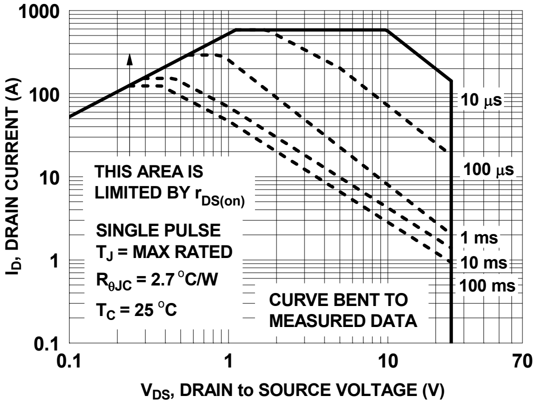


Figure 11. Forward Bias Safe Operating Area

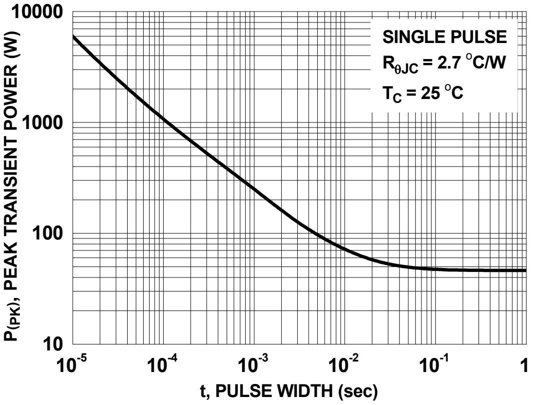


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25 °C unless otherwise noted.

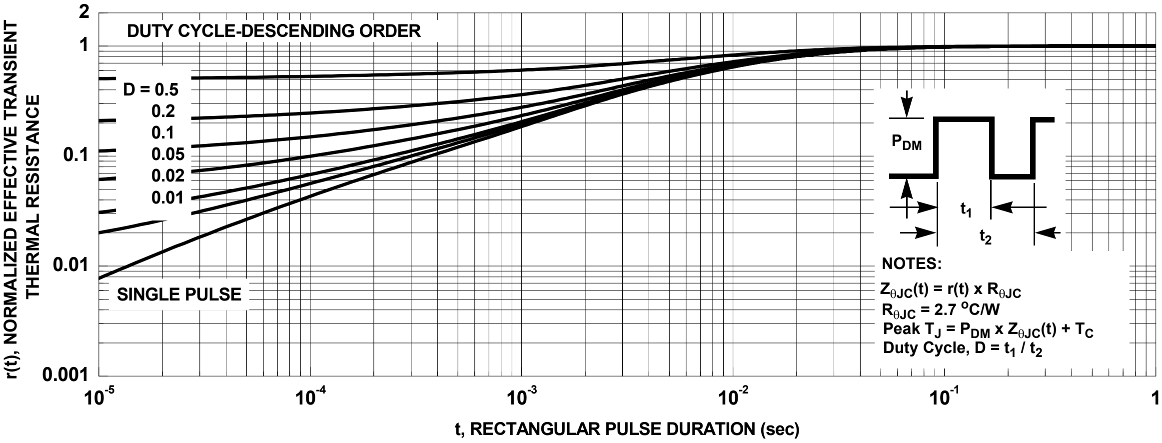


Figure 13. Junction-to-Case Transient Thermal Response Curve

Typical Characteristics (continued)

SyncFET™ Schottky body diode Characteristics

ON's SyncFET™ process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 14 shows the reverse recovery characteristic of the FDMC2D8N025S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

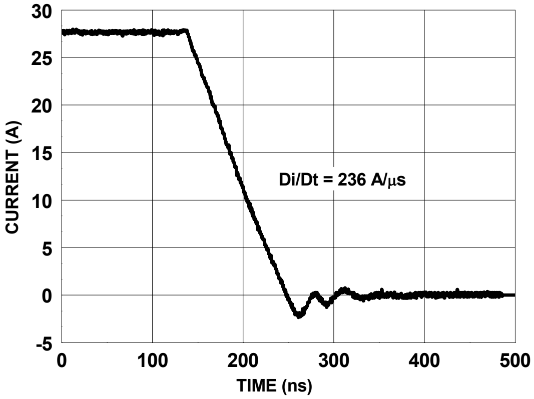


Figure 14. FDMC2D8N025S SyncFET™ Body Diode Reverse Recovery Characteristic

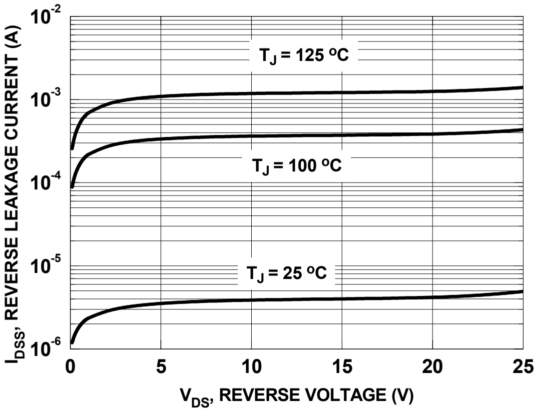
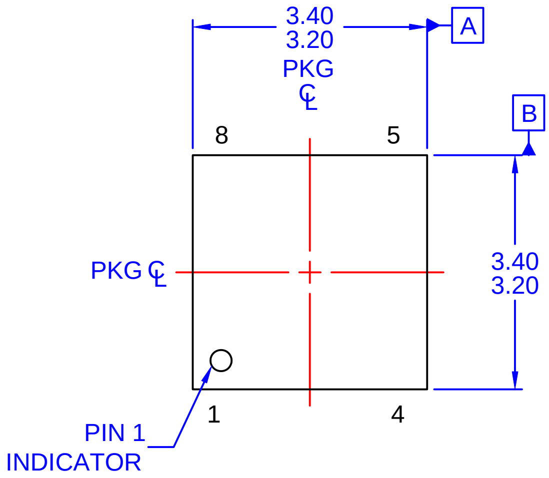
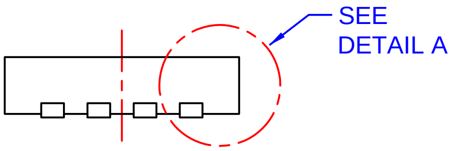
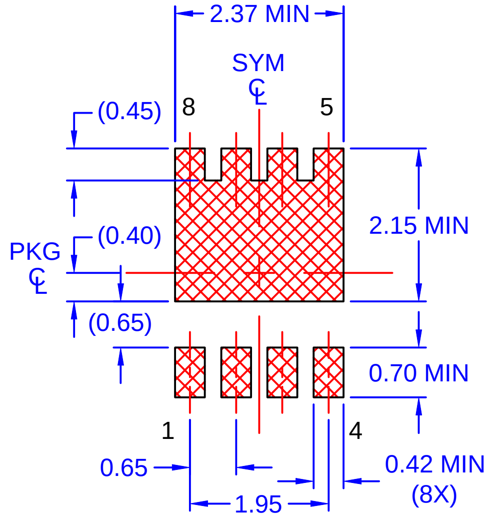


Figure 15. SyncFET™ Body Diode Reverse Leakage vs. Drain-Source Voltage







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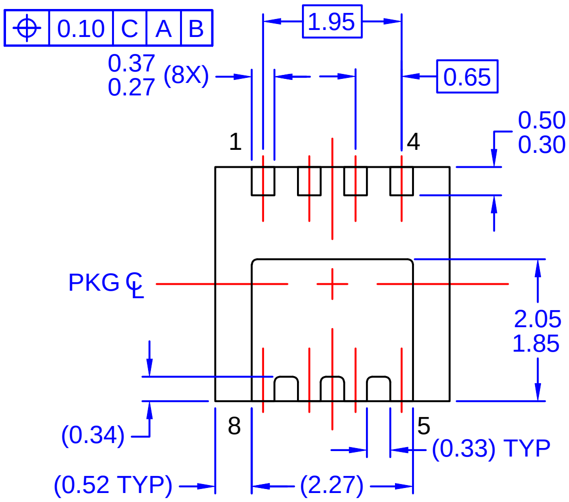

NOTES: UNLESS OTHERWISE SPECIFIED

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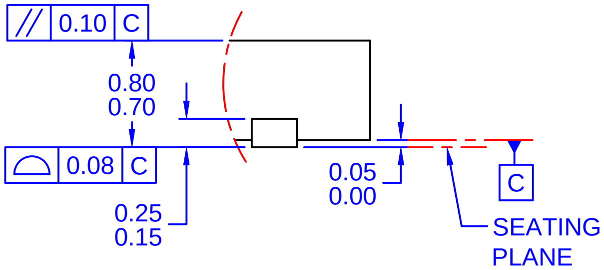

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